JAN 2 & ZOUZ

Form PTO-1449 S. Dept. of Commerce, Patent and Trademarks LIST OF ART CITED BY APPLICANT (Use several sheets if necessary Attorney Docket No. Serial No. Filing Date A-6237 09/729,523 **DECEMBER 4, 2000** Applicant: Group 2131 BACON ET AL. U.S. PATÉNT DOCUMENTS Exami Document No. Date Name Class Subclass ner's **Initial** A.5 5,903,314 5/11/99 Niijima et al. 348 564 AAAB AC AD Jenter 21 icchnology ΑE FOREIGN PATENT DOCUMENTS Document No. Date Country Class Subclass Translation AF AG AH ΑI OTHER PRIOR ART (Including Author Title, Date, Pertinent Pages, Etc.) ΑŢ AK AL DATE CONSIDERED: 5/3/04 EXAMINER

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Attorney Docket No. Serial No. Filing Date A-6237 09/729,523 DECEMBER 4, 2000 Applicant: Group BACON ET AL. 2131 U.S. PATENT DOCUMENTS Exami Document No. Date Name Class Subclass ner's Initial RECEIVED AS 5,425,101 AA 6/13/95 Woo et al. JUN 1 8 2001 11/17/98 A.S 5,838,873 Blatter et al. AB A.S 5,936,660 8/10/99 Gurantz AC echnology center 210 AD AΕ FOREIGN PATENT DOCUMENTS Document No. Date Country Class Subclass Translation **A.S** EP 0 893 921 1/27/99 AF Europe PCT **A.**S WO 99/57889 11/11/99 AG International AH ΑI OTHER PRIOR ART (Including Author Title, Date, Pertinent Pages, Etc.) ΑJ AK AL DATE CONSIDERED: 5/03/04 EXAMINER EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance. Include copy of this form with

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